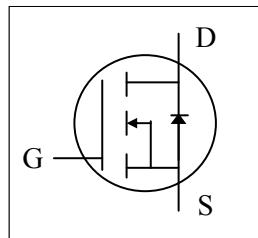
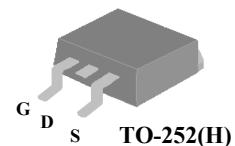




- ▼ 100%  $R_g$  & UIS Test
- ▼ Simple Drive Requirement
- ▼ Low On-resistance
- ▼ RoHS Compliant & Halogen-Free



$BV_{DSS}$	100V
$R_{DS(ON)}$	8.4mΩ
$I_D$	66A



## Description

AP10NA8R4 series are from Advanced Power innovated design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

TO-252 package is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for high current application due to the low connection resistance.

## Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	100	V
$V_{GS}$	Gate-Source Voltage	+20	V
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	66	A
$I_D @ T_C = 100^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	42	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	240	A
$P_D @ T_C = 25^\circ\text{C}$	Total Power Dissipation	69	W
$P_D @ T_A = 25^\circ\text{C}$	Total Power Dissipation <sup>3</sup>	2	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	1.8	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient <sup>3</sup>	62.5	°C/W



## Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	100	-	-	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=30\text{A}$	-	-	8.4	$\text{m}\Omega$
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	2	-	4	V
$\text{g}_{\text{fs}}$	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_D=30\text{A}$	-	50	-	S
$\text{I}_{\text{DSS}}$	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=80\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	25	$\text{uA}$
$\text{I}_{\text{GSS}}$	Gate-Source Leakage	$\text{V}_{\text{GS}}=+20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	+0.1	$\text{uA}$
$\text{Q}_{\text{g}}$	Total Gate Charge	$\text{I}_D=30\text{A}$	-	42	67.2	nC
$\text{Q}_{\text{gs}}$	Gate-Source Charge	$\text{V}_{\text{DS}}=50\text{V}$	-	12	-	nC
$\text{Q}_{\text{gd}}$	Gate-Drain ("Miller") Charge	$\text{V}_{\text{GS}}=10\text{V}$	-	16	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$\text{V}_{\text{DS}}=50\text{V}$	-	14	-	ns
$t_{\text{r}}$	Rise Time	$\text{I}_D=30\text{A}$	-	70	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$\text{R}_G=7.5\Omega$	-	30	-	ns
$t_{\text{f}}$	Fall Time	$\text{V}_{\text{GS}}=10\text{V}$	-	70	-	ns
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}$	-	2030	3248	pF
$\text{C}_{\text{oss}}$	Output Capacitance	$\text{V}_{\text{DS}}=80\text{V}$	-	300	-	pF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	20	-	pF
$\text{R}_{\text{g}}$	Gate Resistance	f=1.0MHz	-	0.7	1.4	$\Omega$

## Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{V}_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$\text{I}_S=30\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1.3	V
$t_{\text{rr}}$	Reverse Recovery Time	$\text{I}_S=30\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	55	-	ns
$\text{Q}_{\text{rr}}$	Reverse Recovery Charge	$d\text{I}/dt=100\text{A}/\mu\text{s}$	-	80	-	nC

## Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT, AUTOMOTIVE OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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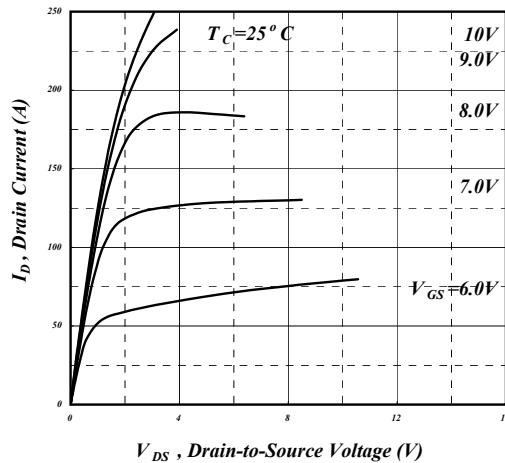


Fig 1. Typical Output Characteristics

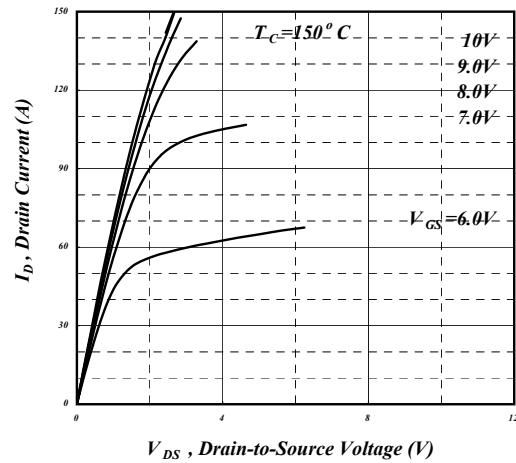


Fig 2. Typical Output Characteristics

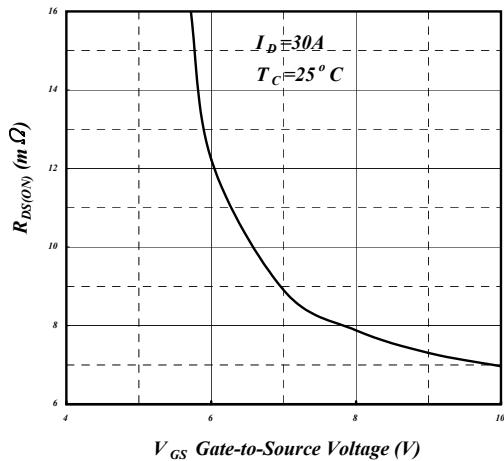


Fig 3. On-Resistance v.s. Gate Voltage

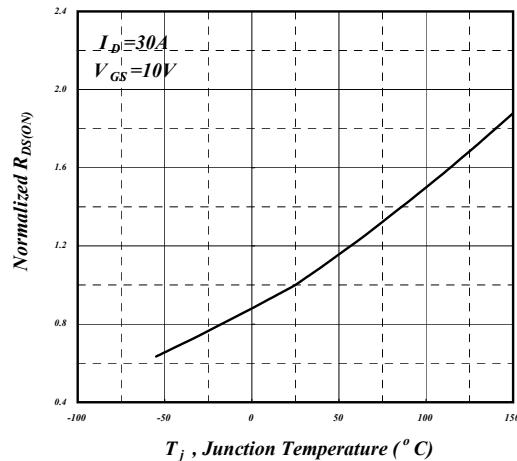


Fig 4. Normalized On-Resistance v.s. Junction Temperature

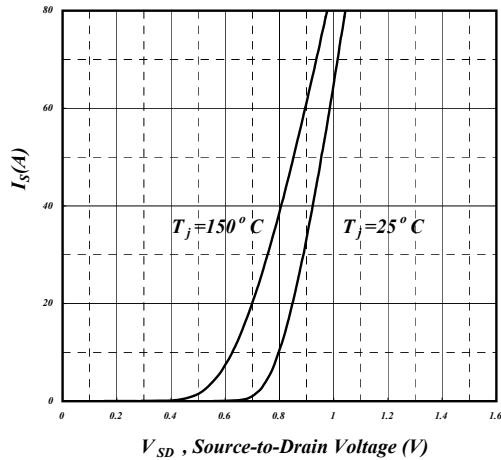


Fig 5. Forward Characteristic of Reverse Diode

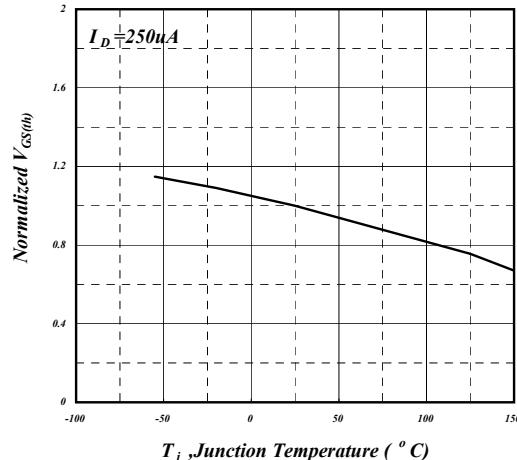
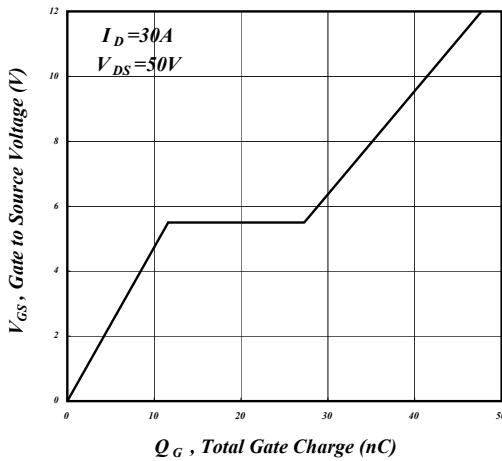
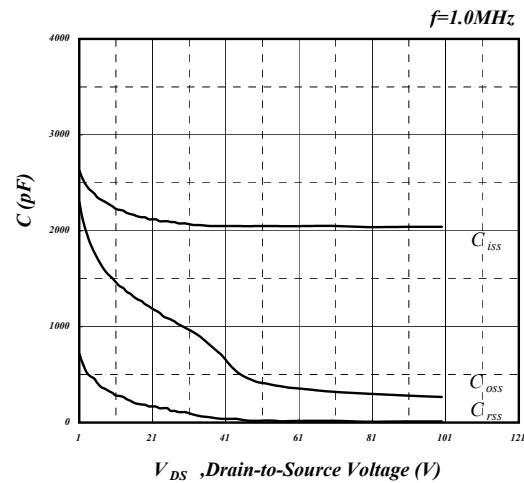


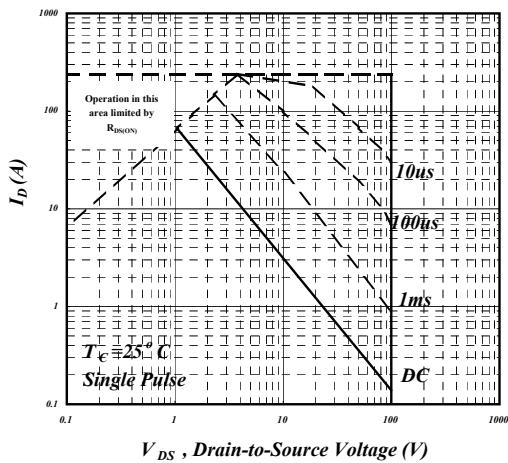
Fig 6. Gate Threshold Voltage v.s. Junction Temperature



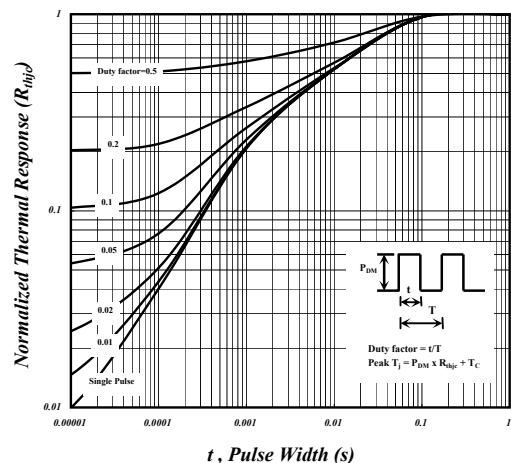
**Fig 7. Gate Charge Characteristics**



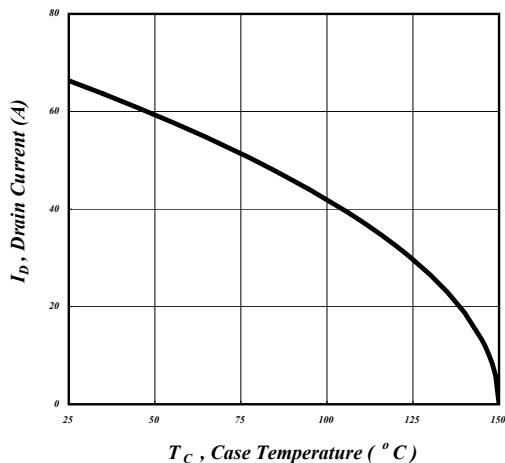
**Fig 8. Typical Capacitance Characteristics**



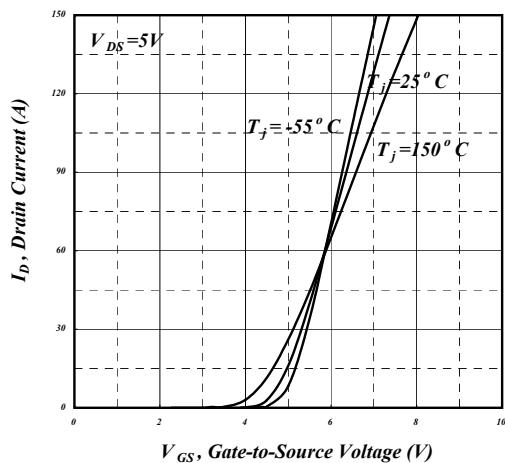
**Fig 9. Maximum Safe Operating Area**



**Fig 10. Effective Transient Thermal Impedance**



**Fig 11. Drain Current v.s. Case Temperature**



**Fig 12. Transfer Characteristics**

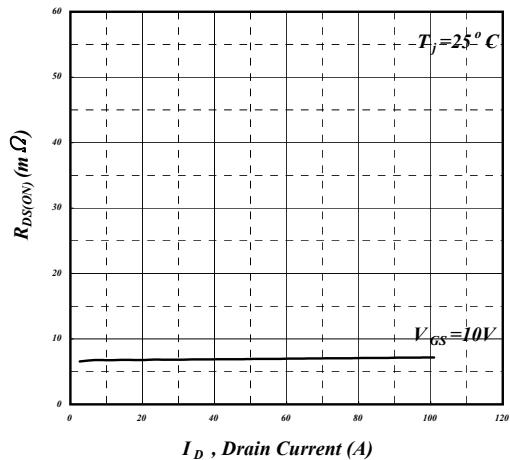


Fig 13. Typ. Drain-Source on State  
Resistance

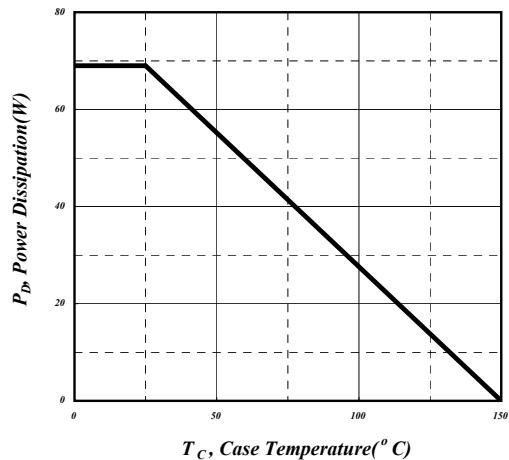


Fig 14. Total Power Dissipation



**AP10NA8R4H**

## **MARKING INFORMATION**

